

Dual N-Channel Enhancement Mode MOSFET

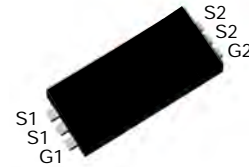
Features

- 20V/8A,
 $R_{DS(ON)}=17.5m\Omega$ (Max.) @ $V_{GS}=4.5V$
 $R_{DS(ON)}=18.5m\Omega$ (Max.) @ $V_{GS}=4V$
 $R_{DS(ON)}=22m\Omega$ (Max.) @ $V_{GS}=3.1V$
 $R_{DS(ON)}=27.5m\Omega$ (Max.) @ $V_{GS}=2.5V$
- Reliable and Rugged
- Lead Free and Green Devices Available (RoHS Compliant)

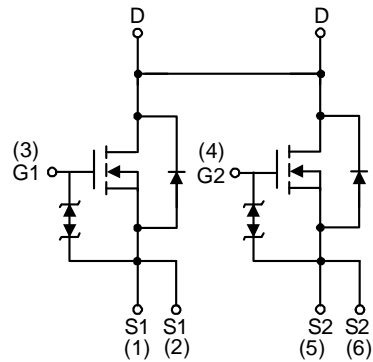
Applications

- Power Management in Notebook Computer, Portable Equipment and Battery Powered Systems.

Pin Description



Top View of TDFN2x5- 6



N- Channel MOSFET

DEVICE MARKING AND ORDERING INFORMATION

Device	Marking	Shipping
FTK9988DFN25	APM9988	3000/Tape&Reel



FTK9988DFN25

Absolute Maximum Ratings (T_A = 25°C Unless Otherwise Noted)

Symbol	Parameter	Rating	Unit	
V _{DSS}	Drain-Source Voltage	20	V	
V _{GSS}	Gate-Source Voltage	±12		
I _D	Continue Drain Current	8**	A	
I _{DM}	300µs Pulsed Drain Current			40
I _S	Diode continuous forward current	1.5	A	
T _J	Maximum Junction Temperature	150	°C	
T _{STG}	Storage Temperature Range	-55 to 150		
P _D	Maximum Power Dissipation	T _A =25°C	3.5	W
		T _A =85°C	1.8	
R _{θJA} *	Thermal Resistance-Junction to Ambient	36	°C/W	
R _{θJC} *	Thermal Resistance-Junction to Case	5.6	°C/W	

Note *Surface Mounted on 1in² pad area, t ≤ 10sec.

** Current limited by bond wire.

Electrical Characteristics (T_A = 25°C Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	FTK9988DFN25			Unit
			Min.	Typ.	Max.	
Static Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =250µA	20	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =16V, V _{GS} =0V	-	-	1	µA
		T _J =85°C	-	-	30	
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250µA	0.5	0.7	1	V
I _{GSS}	Gate Leakage Current	V _{GS} =±10V, V _{DS} =0V	-	-	±10	µA
R _{DS(ON)} ^a	Drain-Source On-state Resistance	V _{GS} =4.5V, I _{DS} =4A	10.5	12.5	17.5	mΩ
		V _{GS} =4V, I _{DS} =4A	11	13	18.5	
		V _{GS} =3.1V, I _{DS} =4A	11.5	14.5	22	
		V _{GS} =2.5V, I _{DS} =4A	15	18	27.5	
Diode Characteristics						
V _{SD} ^a	Diode Forward Voltage	I _{SD} =1.5A, V _{GS} =0V	-	0.7	1.3	V
t _{rr}	Reverse Recovery Time	I _{SD} =4A, dI _{SD} /dt=100µs	-	15	-	nS
Q _{rr}	Reverse Recovery Charge		-	7	-	nC



FTK9988DFN25

Electrical Characteristics(Cont.) (T_A = 25°C Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	FTK9988DFN25			Unit
			Min.	Typ.	Max.	
Dynamic Characteristics^b						
R _G	Gate Resistance	V _{GS} =0V, V _{DS} =0V, F=1MHz	-	4	-	Ω
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =10V, Frequency=1.0MHz	-	950	-	pF
C _{oss}	Output Capacitance		-	175	-	
C _{rss}	Reverse Transfer Capacitance		-	150	-	
t _{d(ON)}	Turn-on Delay Time	V _{DD} =10V, R _L =10Ω, I _{DS} =1A, V _{GEN} =4.5V, R _G =6Ω	-	6	12	ns
t _r	Turn-on Rise Time		-	11	21	
t _{d(OFF)}	Turn-off Delay Time		-	48	87	
t _f	Turn-off Fall Time		-	21	39	
Gate Charge Characteristics^b						
Q _g	Total Gate Charge	V _{DS} =10V, V _{GS} =4.5V, I _{DS} =4A	-	13.5	-	nC
Q _{gs}	Gate-Source Charge		-	1.5	-	
Q _{gd}	Gate-Drain Charge		-	4.5	-	

Note a : Pulse test ; pulse width≤300μs, duty cycle≤2%.

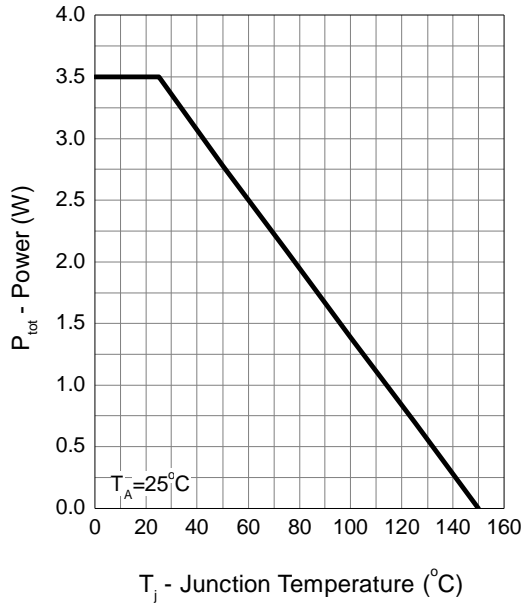
Note b : Guaranteed by design, not subject to production testing.



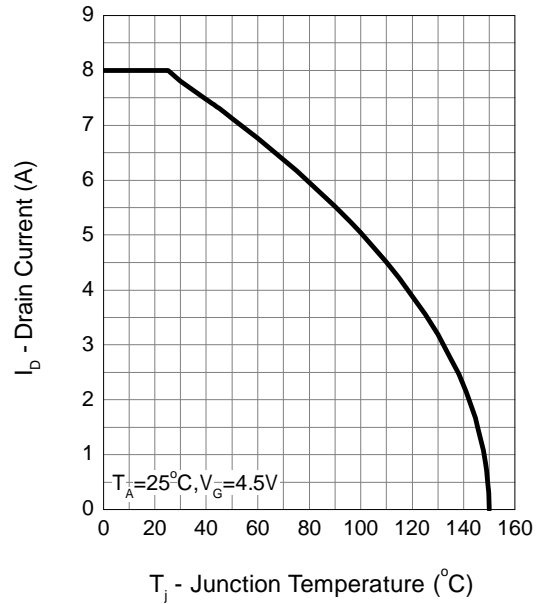
FTK9988DFN25

Typical Operating Characteristics

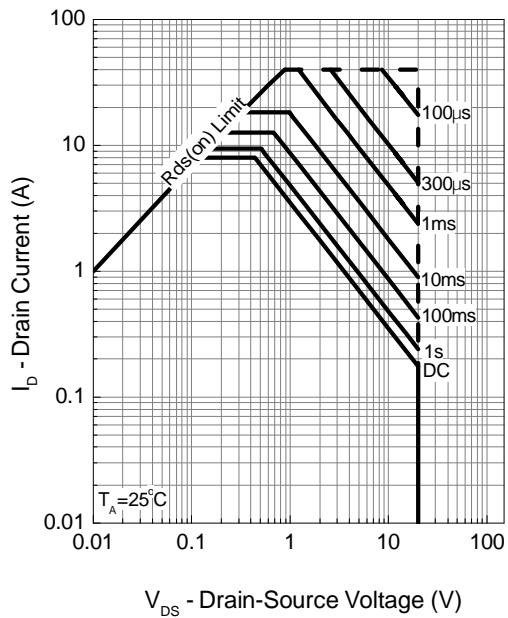
Power Dissipation



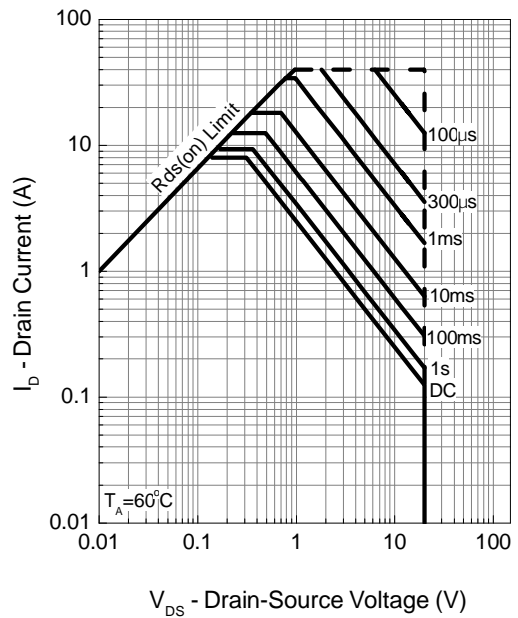
Drain Current



Safe Operation Area ($T_A = 25^\circ\text{C}$)



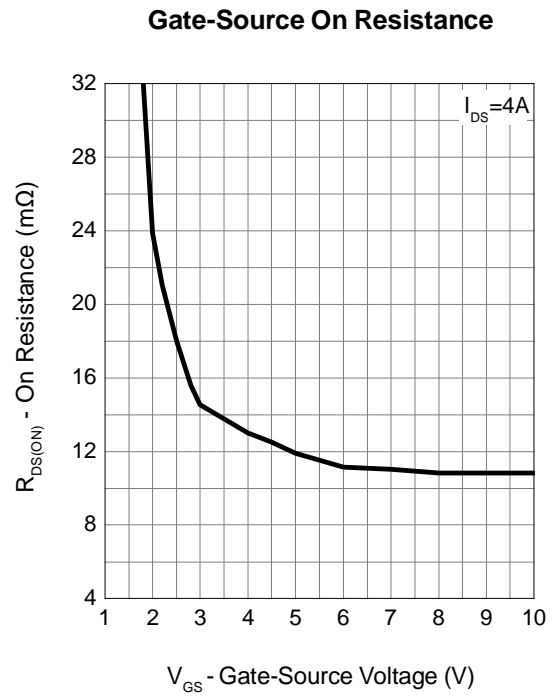
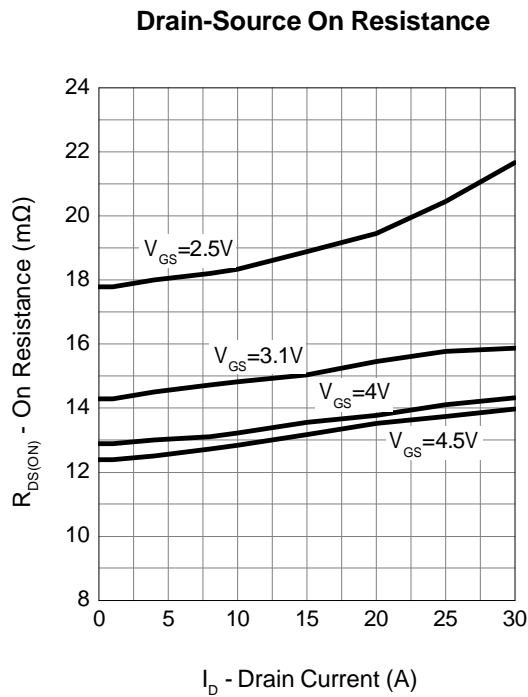
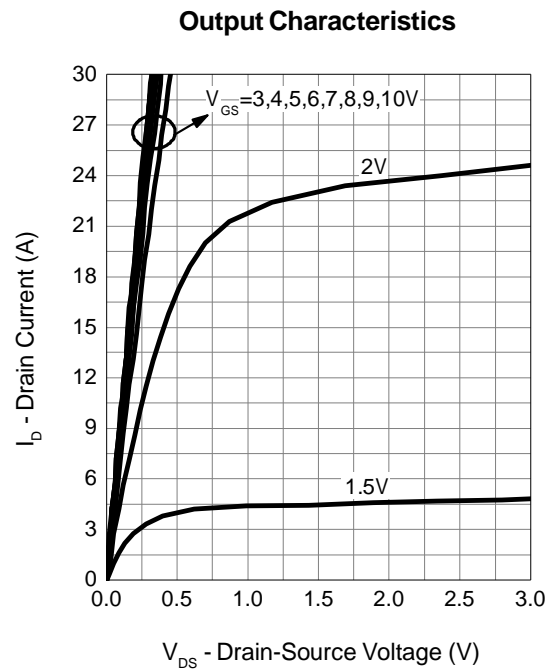
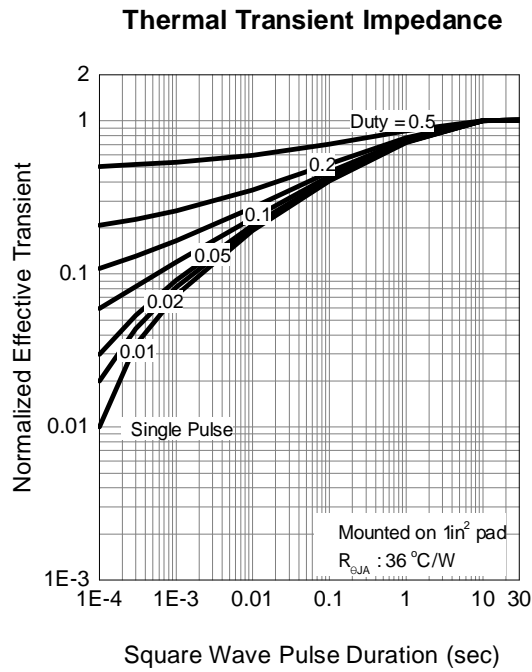
Safe Operation Area ($T_A = 60^\circ\text{C}$)





FTK9988DFN25

Typical Operating Characteristics (Cont.)

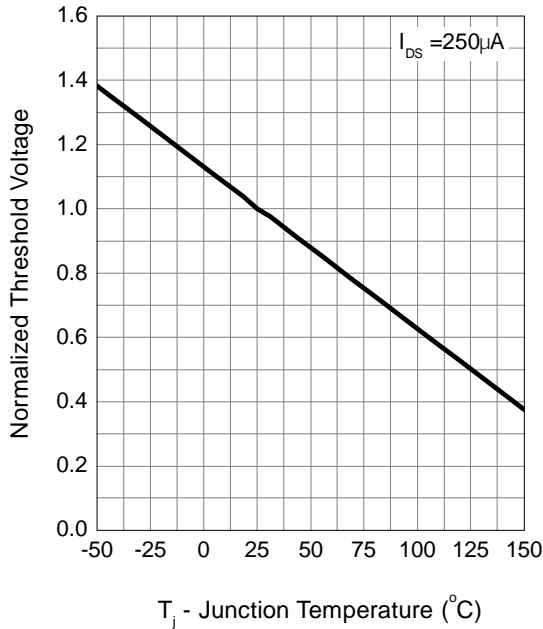




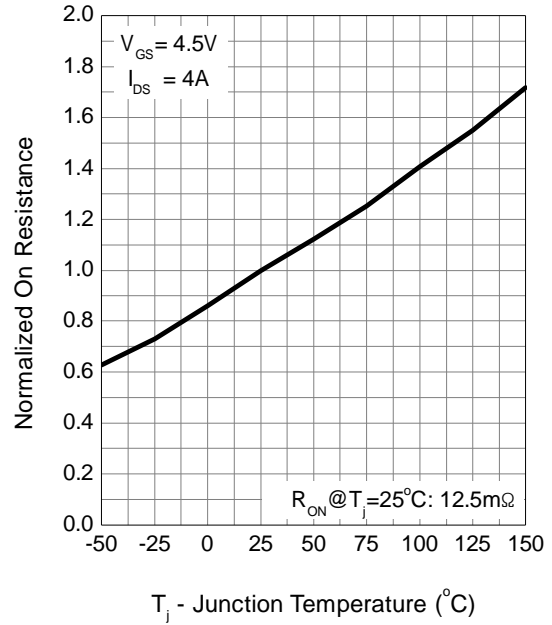
FTK9988DFN25

Typical Operating Characteristics (Cont.)

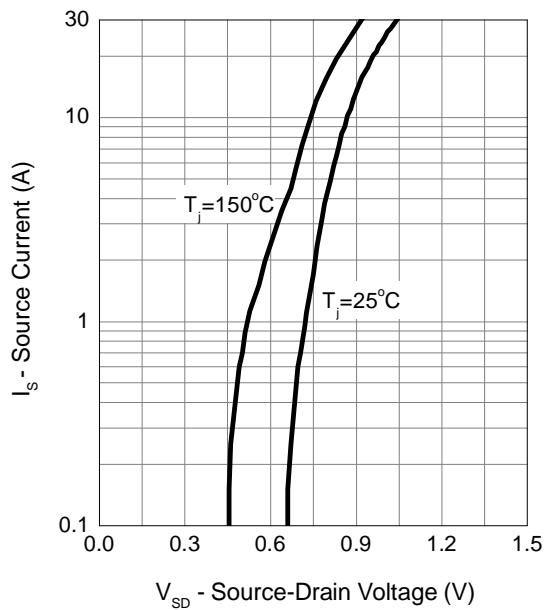
Gate Threshold Voltage



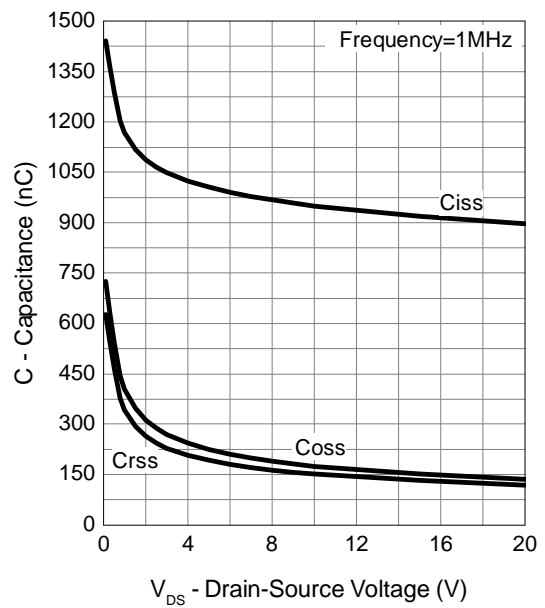
Drain-Source On Resistance



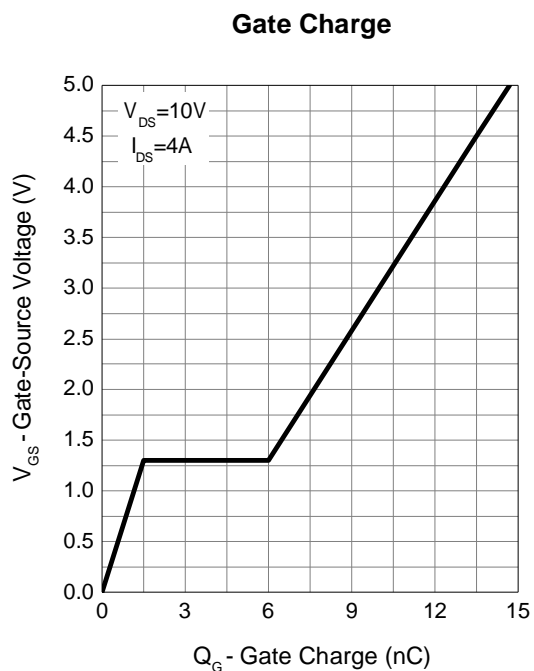
Source-Drain Diode Forward



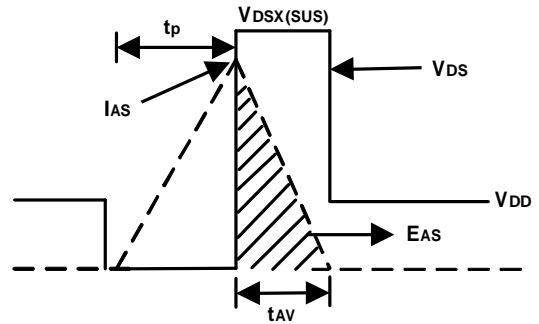
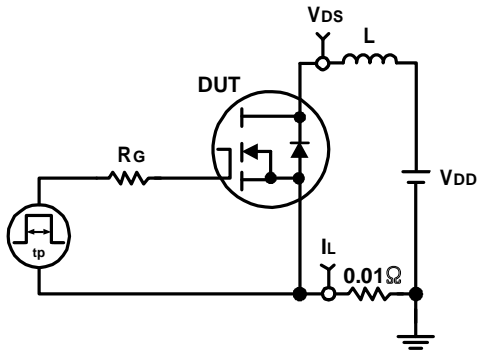
Capacitance



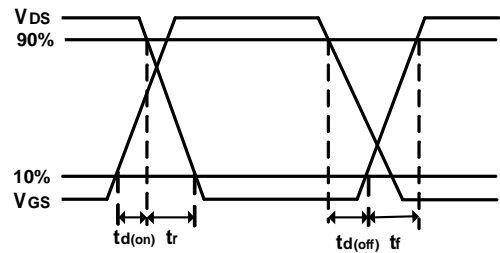
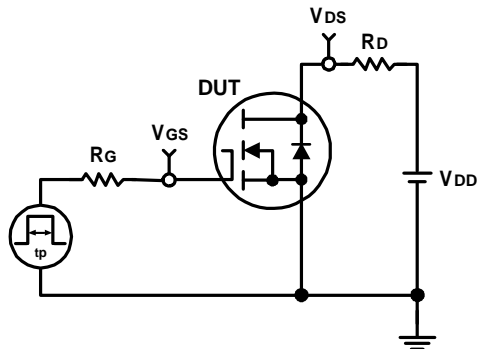
Typical Operating Characteristics (Cont.)



Avalanche Test Circuit and Waveforms

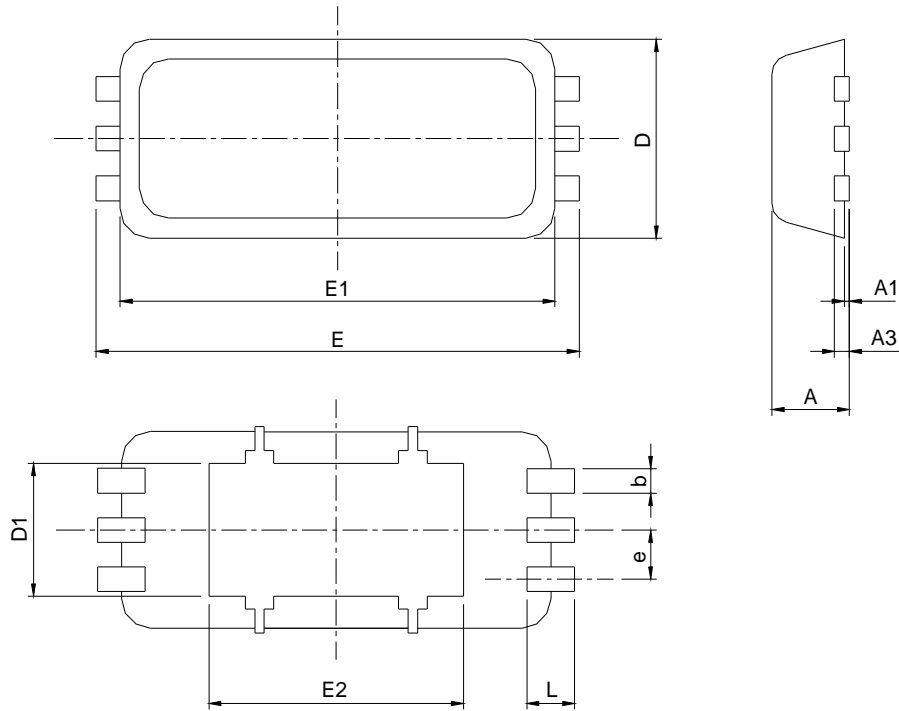


Switching Time Test Circuit and Waveforms



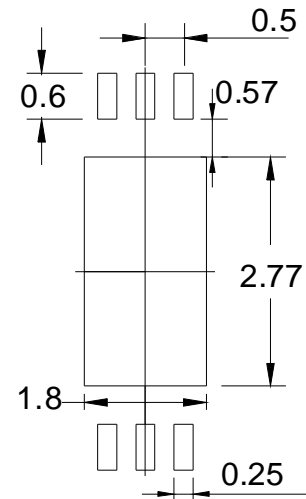
Package Information

TDFN2x5-6



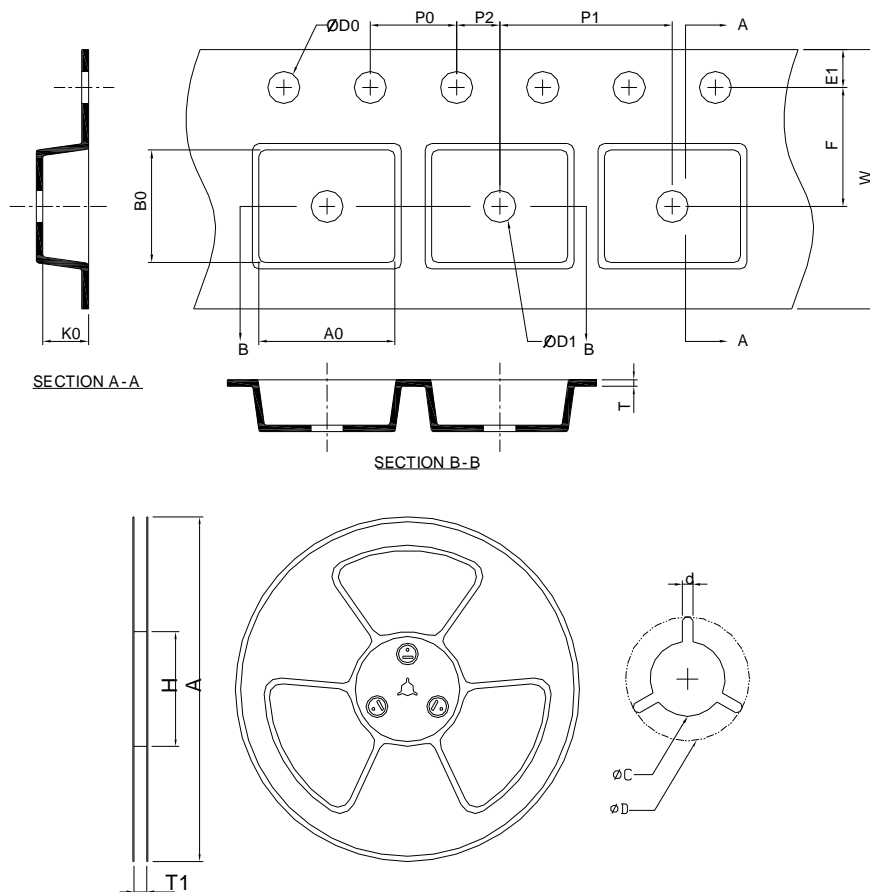
SYMBOL	TDFN2x5-6			
	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	0.70	0.80	0.028	0.031
A1	0.00	0.05	0.000	0.002
A3	0.10	0.20	0.004	0.008
b	0.20	0.30	0.008	0.012
D	1.90	2.10	0.075	0.083
D1	1.30	1.55	0.051	0.061
E	4.80	5.20	0.189	0.205
E1	4.40	4.60	0.173	0.181
E2	2.60	2.95	0.102	0.116
e	0.50 BSC		0.020 BSC	
L	0.40	0.60	0.016	0.024

RECOMMENDED LAND PATTERN



UNIT: mm

Carrier Tape & Reel Dimensions

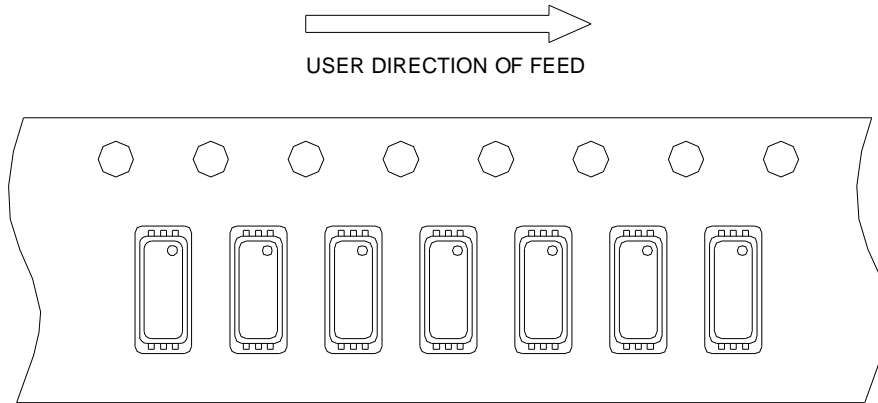


Application	A	H	T1	C	d	D	W	E1	F
TDFN2x5-6	178.0±2.00	50 MIN.	8.4+2.00 -0.00	13.0+0.50 -0.20	1.5 MIN.	20.2 MIN.	8.0±0.20	1.75±0.10	5.5±0.10
	P0	P1	P2	D0	D1	T	A0	B0	K0
	4.0±0.10	4.0±0.10	2.0±0.50	1.5+0.10 -0.00	1.5 MIN.	0.6+0.00 -0.40	2.41±0.20	5.34±0.20	1.10±0.20

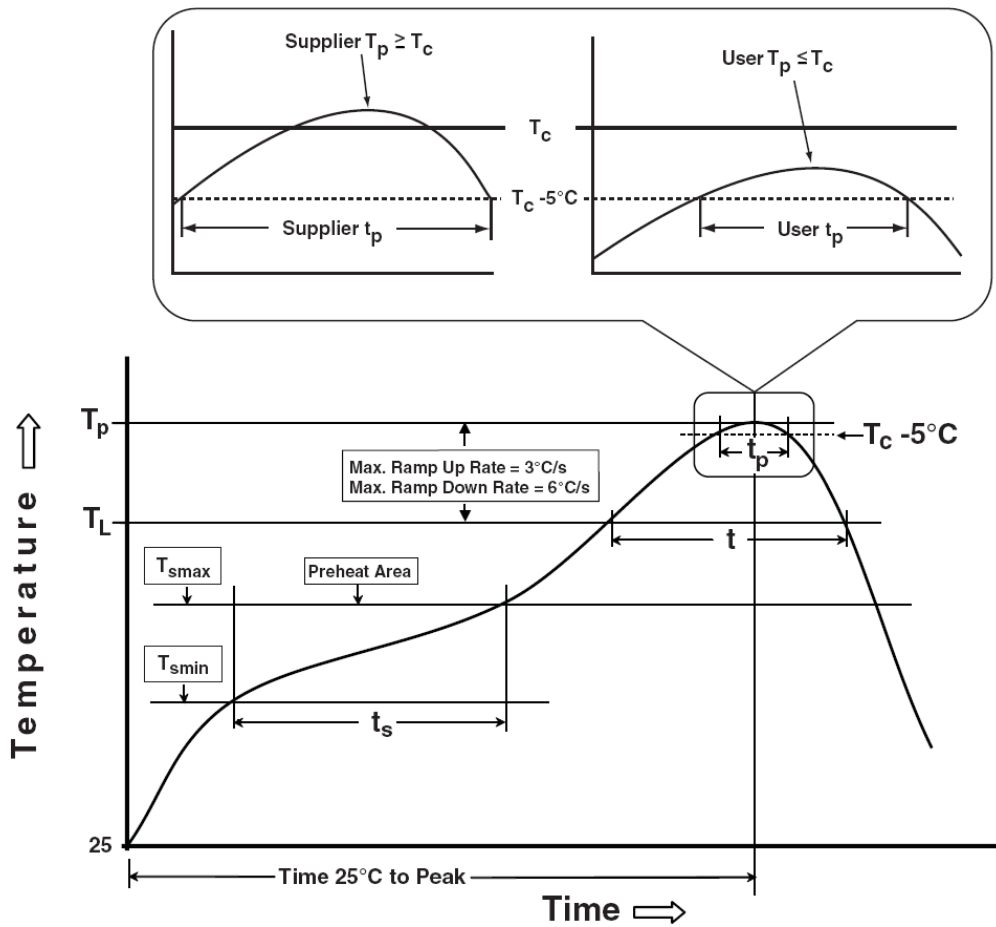
(mm)

Taping Direction Information

TDFN2x5-6



Classification Profile





Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Preheat & Soak Temperature min (T_{smin}) Temperature max (T_{smax}) Time (T_{smin} to T_{smax}) (t_s)	100 °C 150 °C 60-120 seconds	150 °C 200 °C 60-120 seconds
Average ramp-up rate (T_{smax} to T_p)	3 °C /second max.	3 °C /second max.
Liquidous temperature (T_L) Time at liquidous (t_L)	183 °C 60-150 seconds	217 °C 60-150 seconds
Peak package body Temperature (T_p)*	See Classification Temp in table 1	See Classification Temp in table 2
Time (t_p)** within 5 °C of the specified classification temperature (T_c)	20** seconds	30** seconds
Average ramp-down rate (T_p to T_{smax})	6 °C /second max.	6 °C /second max.
Time 25 °C to peak temperature	6 minutes max.	8 minutes max.
* Tolerance for peak profile Temperature (T_p) is defined as a supplier minimum and a user maximum. ** Tolerance for time at peak profile temperature (t_p) is defined as a supplier minimum and a user maximum.		

Table 1. SnPb Eutectic Process – Classification Temperatures (T_c)

Package Thickness	Volume mm ³ <350	Volume mm ³ ≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2. Pb-free Process – Classification Temperatures (T_c)

Package Thickness	Volume mm ³ <350	Volume mm ³ 350-2000	Volume mm ³ >2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245 °C
HTRB	JESD-22, A108	1000 Hrs, 80% of VDS max @ T_{jmax}
HTGB	JESD-22, A108	1000 Hrs, 100% of VGS max @ T_{jmax}
PCT	JESD-22, A102	168 Hrs, 100%RH, 2atm, 121 °C
TCT	JESD-22, A104	500 Cycles, -65 °C ~150 °C